

**Search Notes**

Application/Control No.

10/624,759

Examiner

Sangwoo Ahn

Applicant(s)/Patent under  
Reexamination

WEN ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	1-10	2/17/2006	SW
	100-104.1	2/17/2006	SW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search History Attached (USPGPUB, USPAT, JPO, EPO, DERWENT, IBM_TDB) text search only	2/17/2006	SW
Consulted Hosain Alam	2/17/2006	SW
Consulted Khanh Pham	2/17/2006	SW
Consulted 101 Panel (William Grant)	2/17/2006	SW